A5G35H110N Airfast RF Power GaN Transistor

Rev. 1 — November 2022

This 15.1 W asymmetrical Doherty RF power GaN transistor is designed for cellular base station applications requiring very wide instantaneous bandwidth capability covering the frequency range of 3300 to 3700 MHz.

This part is characterized and performance is guaranteed for applications operating in the 3300 to 3700 MHz band. There is no guarantee of performance when this part is used in applications designed outside of these frequencies.

3500 MHz

 Typical Doherty Single-Carrier W-CDMA Reference Circuit Performance: V_{DD} = 48 Vdc, I_{DQA} = 70 mA, V_{GSB} = -4.1 Vdc, P_{out} = 15.1 W Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. ⁽¹⁾

| Frequency | G _{ps} (dB) | η _D (%) | Output PAR (dB) | ACPR (dBc) |
|-----------|-------------------------|-----------------------|--------------------|---------------|
| 3300 MHz | 14.8 | 57.6 | 7.5 | -27.9 |
| 3400 MHz | 15.4 | 55.7 | 7.8 | -29.3 |
| 3500 MHz | 15.8 | 54.0 | 8.0 | -30.8 |
| 3600 MHz | 15.8 | 54.3 | 7.8 | -31.1 |
| 3700 MHz | 14.9 | 54.3 | 7.4 | -31.0 |

1. All data measured in reference circuit with device soldered to printed circuit board.

Features

- · High terminal impedances for optimal broadband performance
- Improved linearized error vector magnitude with next generation signal
- Able to withstand extremely high output VSWR and broadband operating conditions
- Designed for low complexity linearization systems
- Optimized for massive MIMO active antenna systems for 5G base stations



Note: Exposed backside of the package is the source terminal for the transistor.

Figure 1. Pin Connections



Table 1. Maximum Ratings

| Rating | Symbol | Value | Unit |
|---|-------------------|-------------|------|
| Drain-Source Voltage | V _{DSS} | 125 | Vdc |
| Gate-Source Voltage | V _{GS} | -16, 0 | Vdc |
| Operating Voltage | V _{DD} | 55 | Vdc |
| Maximum Forward Gate Current, $I_{G (A+B)}$, @ $T_{C} = 25^{\circ}C$ | I _{GMAX} | 13.3 | mA |
| Storage Temperature Range | T _{stg} | −65 to +150 | °C |
| Case Operating Temperature Range | T _C | −55 to +150 | °C |
| Maximum Channel Temperature | Т _{СН} | 225 | °C |

Table 2. Recommended Operating Conditions

| Characteristic | Symbol | Value | Unit |
|-------------------|-----------------|-------|------|
| Operating Voltage | V _{DD} | 48 | Vdc |

Table 3. Thermal Characteristics

| Characteristic | Symbol | Value | Unit |
|---|----------------------------|---------|------|
| Thermal Resistance by Infrared Measurement, Active Die Surface-to-Case Case Temperature 120°C, P _D = 14.2 W | R _{θJC} (IR) | 2.8 (1) | °C/W |
| Thermal Resistance by Finite Element Analysis, Channel-to-Case Case Temperature 120°C, P _D = 14.2 W | R _{θCHC} (FEA) | 5.9 (2) | °C/W |

Table 4. ESD Protection Characteristics

| Test Methodology | Class |
|---------------------------------------|-------|
| Human Body Model (per JS-001-2017) | 1A |
| Charge Device Model (per JS-002-2014) | C3 |

Table 5. Moisture Sensitivity Level

| Test Methodology | Rating | Package Peak Temperature | Unit |
|--------------------------------------|--------|--------------------------|------|
| Per JESD22-A113, IPC/JEDEC J-STD-020 | 3 | 260 | °C |

Table 6. Electrical Characteristics (T_A = 25°C unless otherwise noted)

| Characteristic | Symbol | Min | Тур | Max | Unit |
|--|---------------------------------------|--------------|------|------------|------|
| Off Characteristics ⁽³⁾ | | | | | |
| (103 111 117, 103 1117) | I _{D(BR)} arrier aking | | | 2.1 3.9 | mAdc |
| (1) 3 1 1 1 1 , 1 (3 1 1 1 1) | I _{GLK} arrier aking | -1.0 -1.0 | | | mAdc |
| On Characteristics — Side A, Carrier | | | | | |
| Gate Threshold Voltage (V _{DS} = 10 Vdc, I _D = 4.6 mAdc) | V _{GS(th)} | -4.6 | -3.0 | -1.9 | Vdc |
| Gate Quiescent Voltage $(V_{DD} = 48 \text{ Vdc}, I_{DA} = 60 \text{ mAdc}, \text{Measured in Functional Test})$ | V _{GSA(Q)} | -3.0 | -2.4 | -2.0 | Vdc |
| Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = -8 Vdc) | I _{GSS} | -2.1 | _ | | mAdc |
| On Characteristics — Side B, Peaking | <u>.</u> | | | | |
| Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 8.7 \text{ mAdc})$ | V _{GS(th)} | -4.6 | -3.0 | -1.9 | Vdc |
| Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = -8 Vdc) | I _{GSS} | -3.9 | — | — | mAdc |

1. Refer to AN1955, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.nxp.com/RF and search for AN1955.

2. R_{0CHC} (FEA) must be used for purposes related to reliability and limitations on maximum channel temperature. MTTF may be estimated

by the expression MTTF (hours) = $10^{[A + B/(T + 273)]}$, where T is the channel temperature in degrees Celsius, A = -11.1 and B = 8366.

Each side of device measured separately.

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(continued)

| Characteristic | Symbol | Min | Тур | Max | Unit |
|--|-----------------------------|---------------------------|---------------------------|---------------------------|----------|
| Functional Tests ⁽¹⁾ (In NXP Doherty Production Test Fixture, 50 ohm sy P _{out} = 12.6 W Avg., f = 3500 MHz, 1–tone CW. | stem) V _{DD} = 48 | 8 Vdc, I _{DQA} = | 60 mA, V _{GSB} | = (V _t – 1.65) | Vdc, |
| Power Gain | G _{ps} | 13.0 | 15.3 | 19.0 | dB |
| Drain Efficiency | η _D | 40.0 | 45.3 | — | % |
| Pout @ 6 dB Compression Point | P6dB | 46.0 | 47.6 | _ | dBm |
| Wideband Ruggedness ⁽²⁾ (In NXP Doherty Reference Circuit, 50 ohm sy White Gaussian Noise (AWGN) with 10 dB PAR | vstem) I _{DQA} = 7 | 70 mA, V _{GSB} | =4.1 Vdc, f | = 3500 MHz, <i>i</i> | Additive |
| ISBW of 400 MHz at 55 Vdc, 30.2 W Avg. Modulated Output Power (3 dB Input Overdrive from 15.1 W Avg. Modulated Output Power) | No Device Degradation | | | | |
| Typical Performance ⁽²⁾ (In NXP Doherty Reference Circuit, 50 ohm syst 3400–3600 MHz Bandwidth | em) V _{DD} = 48 | Vdc, I _{DQA} = 7 | ′0 mA, V _{GSB} = | = -4.1 Vdc, | |
| VBW Resonance Point (IMD Third Order Intermodulation Inflection Point) | VBW _{res} | | 300 | | MHz |
| Gain Flatness in 200 MHz Bandwidth @ P _{out} = 15.1 W Avg. | G _F | | 0.4 | | dB |
| Fast CW, 27 ms Sweep | 1 | | | | |
| Pout @ 6 dB Compression Point | P6dB | | 87 | _ | W |
| AM/PM | Φ | | -6 | _ | 0 |
| (Maximum value measured at the P6dB compression point across the 3400–3600 MHz bandwidth) | | | | | |

| Gain Variation over Temperature (–40°C to +85°C) | ∆G | _ | 0.03 | _ | dB/°C |
|---|---------------|---|-------|---|-------|
| Output Power Variation over Temperature (-40°C to +85°C) | $\Delta P6dB$ | — | 0.001 | — | dB/°C |

Table 7. Ordering Information

| Device | Tape and Reel Information | Package |
|--------------|---|-------------|
| A5G35H110NT4 | T4 Suffix = 2,500 Units, 16 mm Tape Width, 13-inch Reel | DFN 7 × 6.5 |

1. Part internally input matched.

2. All data measured in reference circuit with device soldered to printed circuit board.

Correct Biasing Sequence for GaN Depletion Mode Transistors in a Doherty Configuration

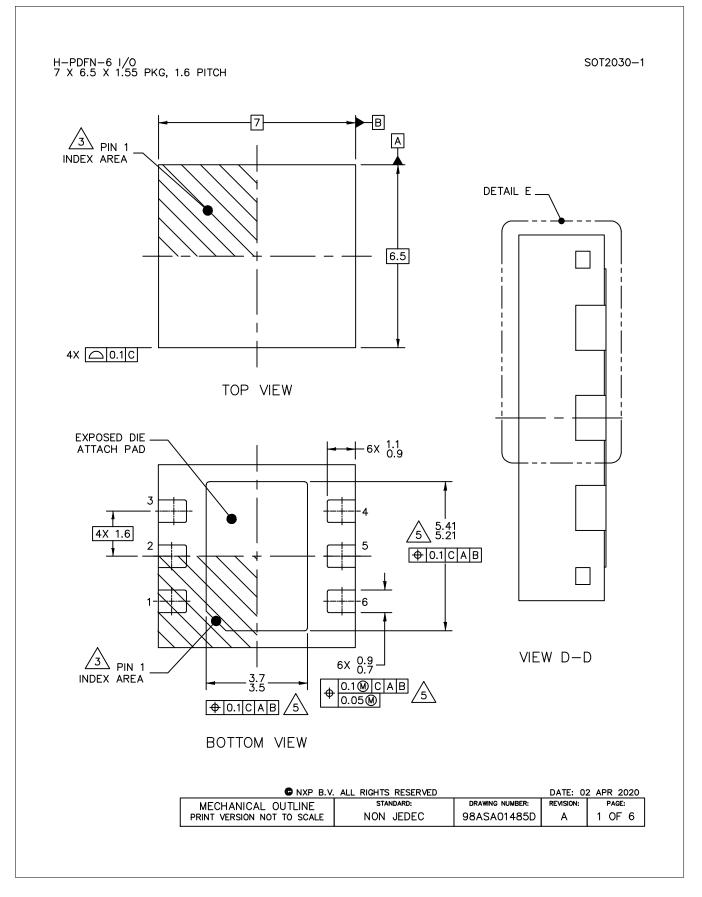
Bias ON the device

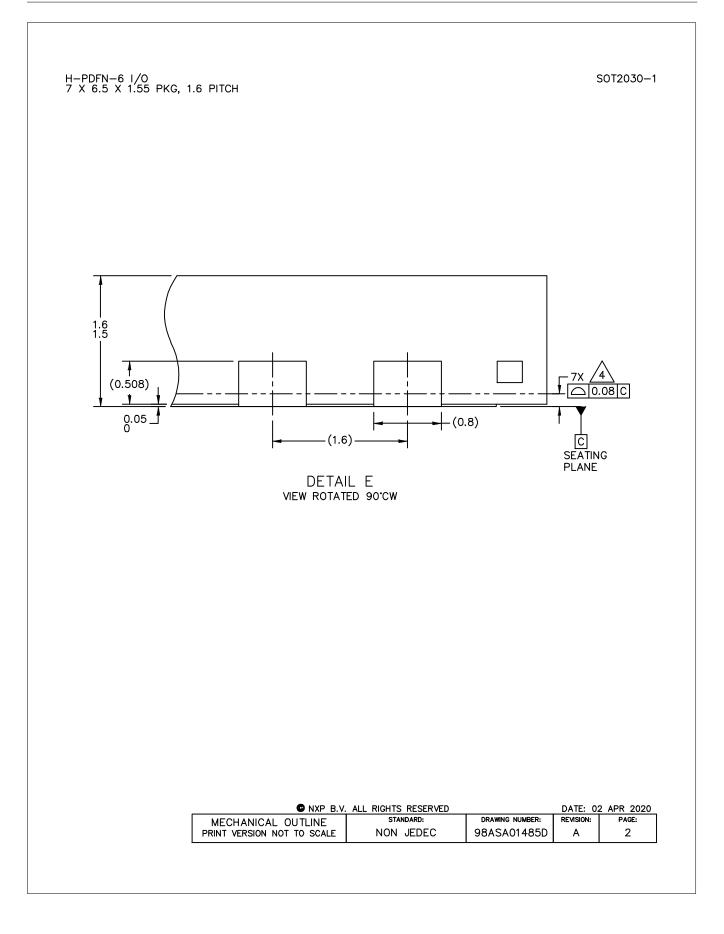
- 1. Set gate voltage V_{GSA} and V_{GSB} to –5 V.
- 2. Set drain voltage V_{DSA} and V_{DSB} to nominal supply voltage (+48 V).
- 3. Increase V_{GSA} (carrier side) until I_{DQA} current is attained.
- 4. Increase $V_{\mbox{GSB}}$ (peaking side) to target bias voltage.
- 5. Apply RF input power to desired level.

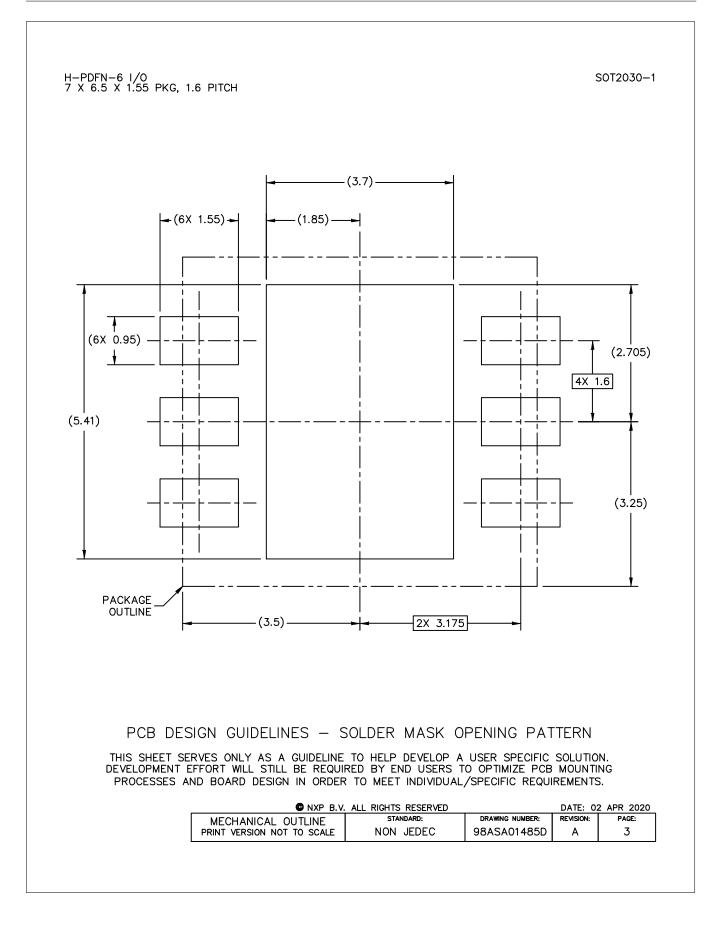
Bias OFF the device

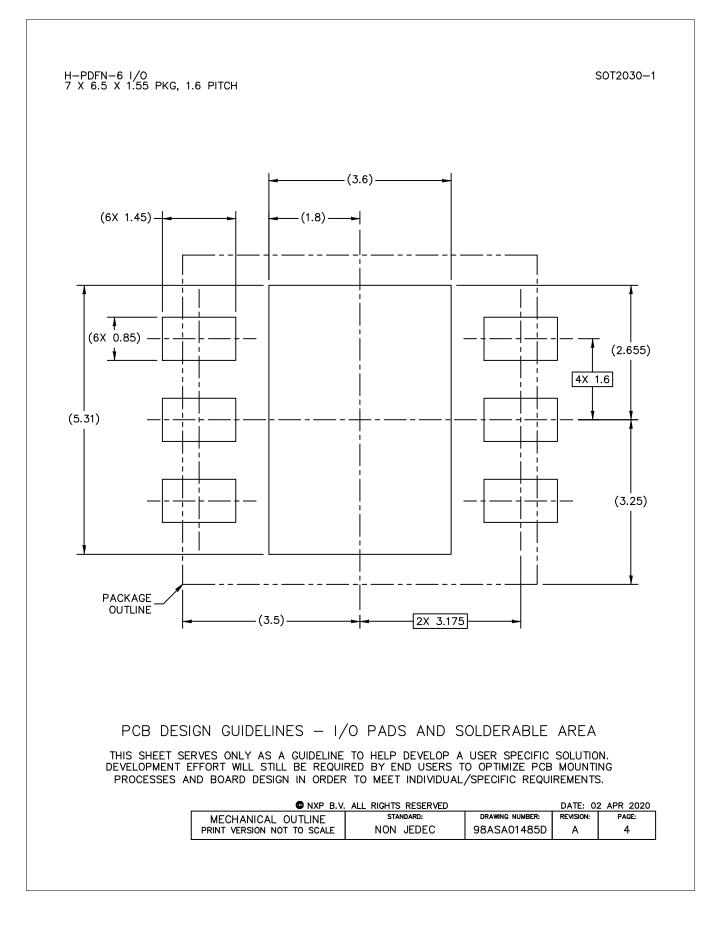
- 1. Disable RF input power.
- 2. Adjust gate voltage V_{GSA} and V_{GSB} to -5 V.
- 3. Adjust drain voltage V_{DSA} and V_{DSB} to 0 V. Allow adequate time for drain voltage to reduce to 0 V from external drain capacitors.
- 4. Disable V_{GSA} and V_{GSB} .

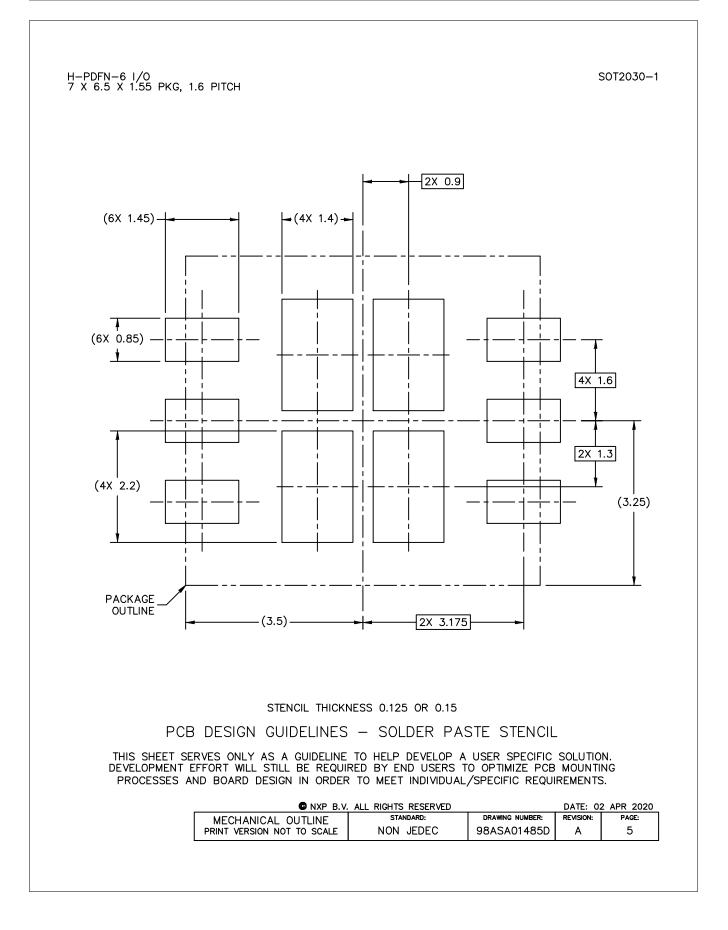
Package Information











H-PDFN-6 I/O 7 X 6.5 X 1.55 PKG, 1.6 PITCH

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- /3. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.
- 4. COPLANARITY APPLIES TO LEADS AND DIE ATTACH FLAG.

5. RADIUS ON LEAD AND DIE ATTACH FLAG IS OPTIONAL.

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Product Documentation and Software

Refer to the following resources to aid your design process.

Application Notes

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Software

.s2p File

Revision History

The following table summarizes revisions to this document.

| Revision | Date | Description |
|----------|-----------|---|
| 0 | Dec. 2021 | Initial release of data sheet |
| 1 | Nov. 2022 | Table 1, Maximum Ratings: Gate-Source Voltage: updated -8, 0 to -16, 0 Vdc, p. 2 Table 4, ESD Protection Characteristics, Human Body Model: updated to reflect test data, p. 2 Table 6, Electrical Characteristics, Off Characteristics: added Off-State Gate Leakage, p. 2 General updates made to align data sheet to current standard |

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> Date of release: November 2022 Document identifier: A5G35H110N